

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/771,556	TANINO ET AL.	
	Examiner	Art Unit	
	Robert M Kun mund	1765	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B	US-6,217,842	04-2001	Tanino	117/951
C	US-6,153,166	11-2000	Tanino	117/4
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K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages		
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.